

INSPECTION APPARATUS

ABSTRACT

An inspection apparatus for inspecting the tension of a tape adhered to an annular frame having, in the center thereof, an opening for accommodating a wafer includes a frame support section that supports the annular frame with the tape adhered thereto, a light source that applies light toward the tape, an imaging camera that captures, through the tape, the light applied from the light source, a first polarizing plate disposed between the tape and the light source, and a second polarizing plate which is disposed between the tape and the imaging camera and positioned such as to shield the light of linearly polarized light transmitted through the first polarizing plate. In a case where distortion is generated in a polarization plane of the light due to application, onto the tape, of the light of the linearly polarized light transmitted through the first polarizing plate, the light is transmitted through the second polarizing plate, and the imaging camera images the transmitted light.

[FIG. 2]